



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Gunther Waitl et al.
Serial No. : 10/616,070
Filed : September 9, 2003
Title : IMPROVED DIODE HOUSING

Art Unit : 2874
Examiner : Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of the Japanese Examination Report from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: Apr 26, 2004

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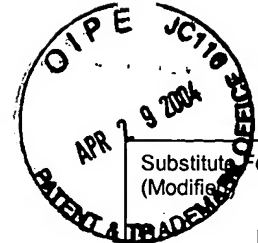
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CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

April 27, 2004
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Signature

Jennifer Leveille
Typed or Printed Name of Person Signing Certificate



Substitute Form PTO-1449 (Modification)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12406-074002	Application No. 10/616,070
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Gunther Waitl et al.	
		Filing Date September 9, 2003	Group Art Unit 2874

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	WO 98/12757	03/26/1998	WIPO				
	AM	WO 97/12404	04/03/1997	WIPO				
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	